

The JEOL-5600 SEM uses a tungsten filament as the electron source. The sample is in high vacuum. Oxford Instruments EDX system is attached for elemental analysis.

Specifications

Maximum resolution	5 nm
Probe current	10^{-12} to 10^{-6} A
Accelerating voltage	0.5 to 30 kV (in 53 steps)
Magnification	25 to 300,000x
Specimen area	Up to 125 mm in diameter
Stage movement	x, y, z, rotate, tilt
Image mode	Secondary electron, backscattered electron
Elemental analysis	For $Z \geq 11$ (elements from Na)